



AOP-8060WT (MPC-5320)
With CFD
Environment Test Report

Report NO: 05P020023

Issued by: **Rex-Chang** / **06/17/2005**

Test Engineer Date

Reviewed by: **Wenyuan Yang** / **06/17/2005**

Manager Date

1. <i>Test item list</i> -----	2
2. <i>Temperature cycle operation test</i> -----	3
3. <i>High temperature storage test</i> -----	6
4. <i>Low temperature storage test</i> -----	7
5. <i>Humidity test</i> -----	8
6. <i>Cold start test</i> -----	9

Num	Item	Spec
1.	Control Box:	AOP- 8060WT / Fanless Operator Panel PC
	1. Main Board	AAEON MPC-5320 Rev. A1.1 (BIOS: AOP- 8060 BIOS Rev: 0.4)
	2.LCD	LG. Philips 6.4" TFT LB064V02-A1 640*480 18 bit
	3.Inverter	ATBEL AV1-01L5V6
	4.Touch Screen	EEILY 6.4" 1TO05S0934.4
	5. CPU	Onboard SiS CPU.BGA.686P.SiS552.200MHz.1.8V
	6. Memory	Onboard 128MB Hynix HY57V561620CTP-H (PC-133)
	7. CFD	SanDisk 64MB
	8. Adapter	EDAC 100/240V.12V.5A.60W.DC.With Lock EA1050A (13)

Test Date: 06-12~16-2005

Test Product: AOP-8060WT (MPC-5320 Rev: A1.1) Fanless Operator Panel PC.

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

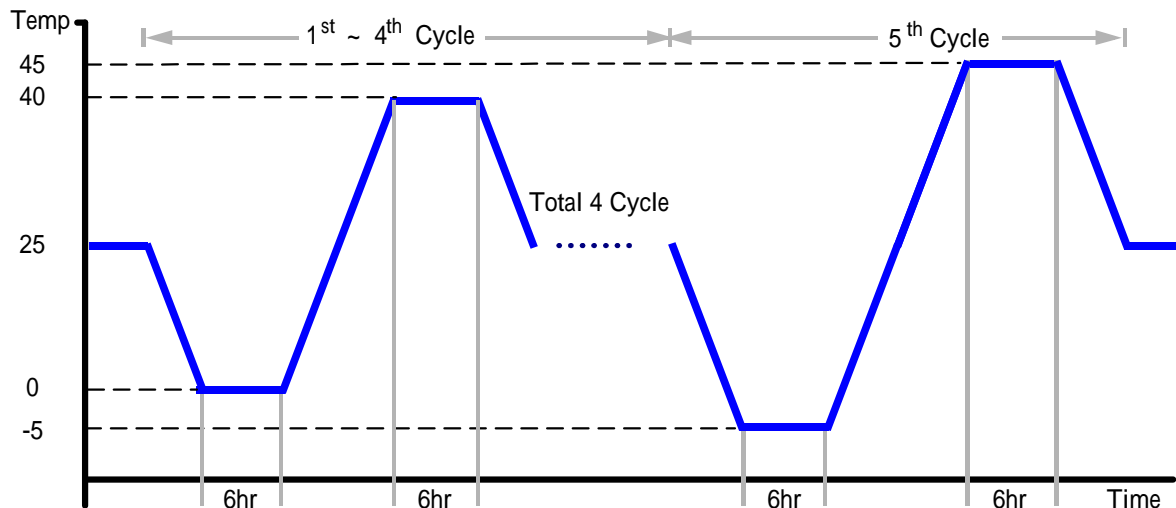
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/23/04
Serial Number: 1241

Temperature Measurement:

20 Channel Thermal Recorder:
YOKOGAWA Inc,
Model: DA100-13-1D
Date of Calibration: 12/25/04
Serial Number: 12A323190

Test Condition:

1. Test Low Temperature: 0 (1~4 cycle)
-5 (5th cycle)
2. Test High Temperature: 40 (1~4 cycle)
45 (5th cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2 /min
5. Test cycle: 5 cycle
6. Test Environment Curve:



Test O.S. / Software:

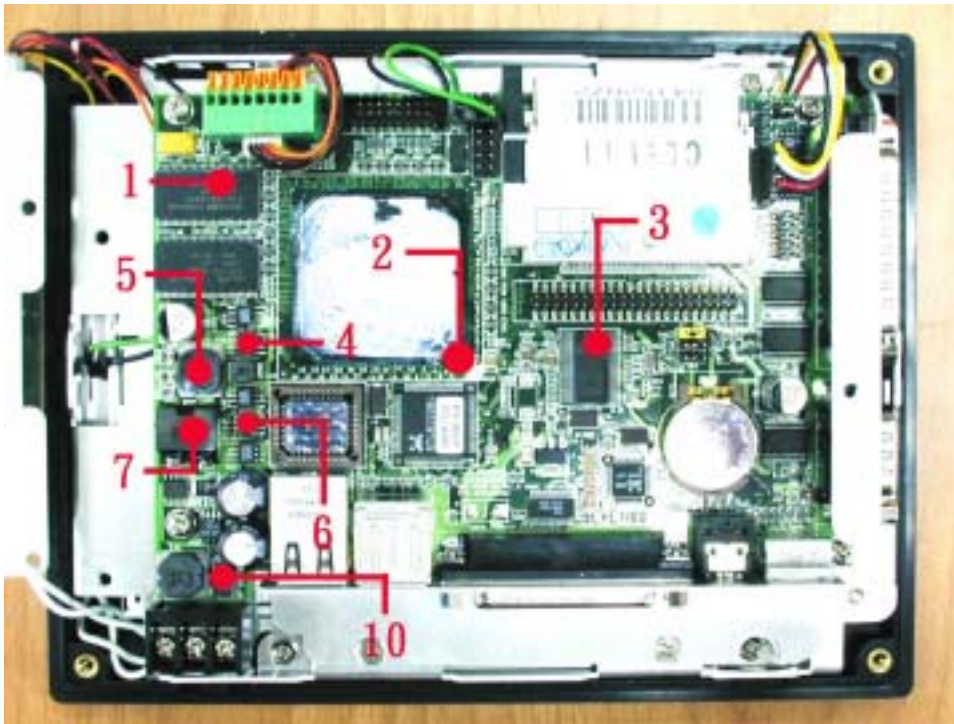
Windows CE / Run Media Player (Non-Audio)

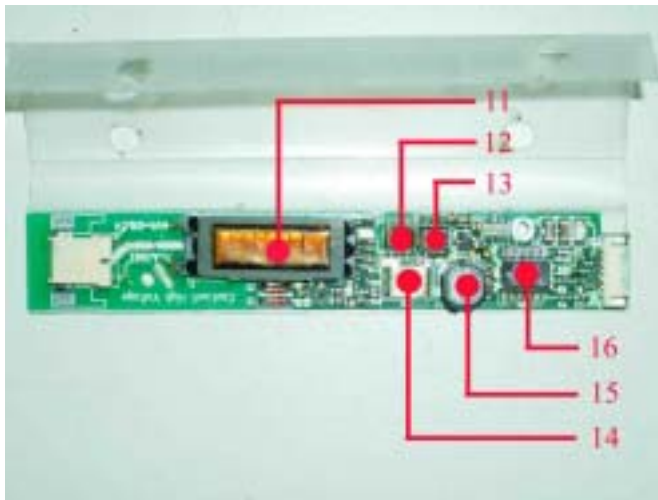
Sample Configuration & Quantity Under Test:

Using one AOP-8060WT (MPC-5320 A1.1) Embedded Control PC

Temperature Recorder:

Measuring Accelerometer Position:





Thermal profile data:

AOP-8060WT (MPC-5320 A1.1) Fanless Operator Panel PC

Point	Temp. Stage()	Spec	45	40	25	0	-5
1. U5 IC.SMD SDRAM.8M*16 PC-133 TSOPII 54P 3.3V. Hynix HY57V561620CTP-H		100	79.9	74.9	59.9	34.9	29.9
2. U32 SiS CPU.BGA.686P.SiS552.200MHz.1.8V		105	75.9	70.9	55.9	30.9	25.9
3. U1 IC.SMD.SSOP 48P.Clock Generator.ICS.ICS951901AF		115	82.2	77.2	62.2	37.2	32.2
4. U28 PWR.SMD SO-8.P-Channel 30V MOSFET.APEC.AP4435M		125	81.1	76.1	61.1	36.1	31.1
5. L48 INDUCTORS.3.3uH 6.5A.20%.SMD 2pin. SMTDR105-3R3M		125	81.6	76.6	61.6	36.6	31.6
6. U30 IC.SMD SOP.8Pin Switching PWM Controller.Intersil.ISL6520A		100	83.7	78.7	63.7	38.7	33.7
7. L47 INDUCTORS.3.2uH 12.8A.20%.SMD 3pin .CEP125U-3R2M		115	83.3	78.3	63.3	38.3	33.3
8. D6 Diode.SMD.DO-214AB.Transient Voltage Suppressor.CONCORD.SMCJ28A		125	71.0	66.0	51.0	26.0	21.0
9. D7 D Schottky.60V.3A.SMD.WILLAS.SK36C		125	84.8	79.8	64.8	39.8	34.8
10.D5 D Schottky.60V.3A.SMD.WILLAS.SK36C		125	77.6	72.6	57.6	32.6	27.6
11. Inverter - T1		N/A	72.2	67.2	52.2	27.2	22.2
12. Inverter - U1		N/A	81.3	76.3	61.3	36.3	31.3
13. Inverter - U2		N/A	79.6	74.6	59.6	34.6	29.6
14. Inverter - CR1		N/A	77.3	72.3	57.3	32.3	27.3
15. Inverter - L1		N/A	77.2	72.2	57.2	32.2	27.2
16. Inverter - CPU		N/A	71.9	66.9	51.9	26.9	21.9
17. Chamber Air Temperature			45.1	40.1	25.1	0.1	-4.9

Note: The description in red states which temperature is over the specification of the device.

Sample Configuration & Quantity Under Test:

Quantity: 1 (AOP-8060WT Fanless Operator Panel PC)

Test Result:

The system structure doesn't deformation; Function is OK during system test.

Test Date: 05-21~23-2005

Test Product: AOP-8060WT (MPC-5320 Rev: A1.1) Fanless Operator Panel PC.

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/24/04
Serial Number: 1241

Testing Item:

1. Test Temperature: 60
2. Test Times: 48Hrs
3. Test Software: Windows CE / Run Media Player from CFD
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AOP-8060WT Fanless Operator Panel PC)

Test Result:

The system structure doesn't have any deformation; All functions are OK after high temperature storage test.

Test Date: 05-19~21-2005

Test Product: AOP-8060WT (MPC-5320 Rev: A1.1) Fanless Operator Panel PC.

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

Test Standard: Reference IEC 68-2-1
Testing procedures Test Ab: Cold Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 05/24/04
Serial Number: 1241

Testing Item:

1. Test Temperature: -20
2. Test Times: 48Hrs
3. Test Software: Windows CE / Run Media Player from CFD
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AOP-8060WT Fanless Operator Panel PC)

Test Result:

The system structure doesn't have any deformation; All functions are OK after low temperature storage test.

Test Date: 05-20~22-2005

Test Product: AOP-8060WT (MPC-5320 Rev: A1.1) Fanless Operator Panel PC.

Test Site: AAEON QA Internal Lab.

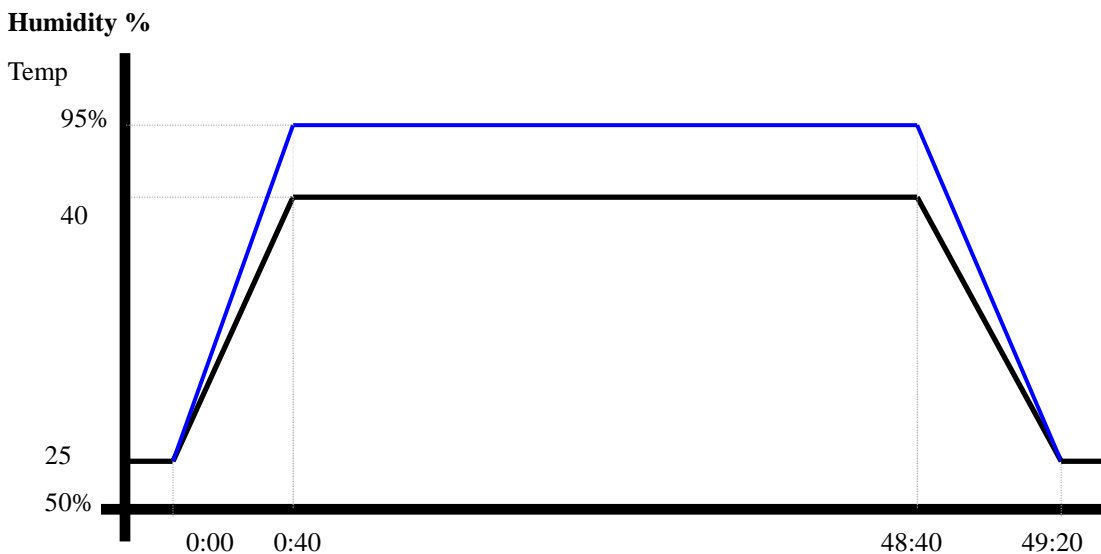
Performed By: Rex Chang

Test Standard: Reference IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 10/17/03
Serial Number: 2582

Testing Item:

1. Test Temperature: 40
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows CE / Run Media Player from CFD
5. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (AOP-8060WT Fanless Operator Panel PC)

Test Result:
The system structure doesn't have any deformation; All functions are OK after humidity test.

Test Date: 05-23~24-2005

Test Product: AOP-8060WT (MPC-5320 Rev: A1.1) Fanless Operator Panel PC.

Test Site: AAEON QA Internal Lab.

Performed By: Rex Chang

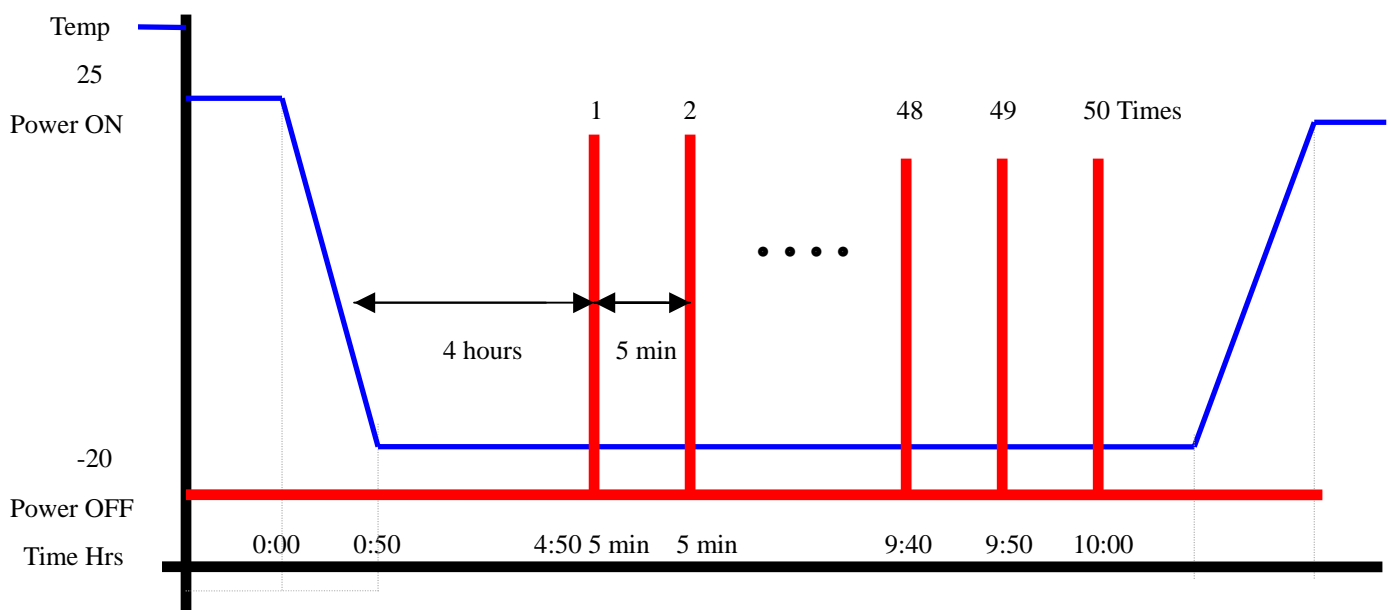
Test Standard: Reference IEC 68-2-1 Testing procedures
Test Ab: Cold Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: TS-F3L+-100
Date of Calibration: 04/02/04
Serial Number: 1467

Test Condition:

1. Test Temperature: -20
2. Test Times: 5 Hours or 50 times of ON/OFF
 - (1) Power off for 4 hours before 1'st power on. Then once complete boot, power off immediately.
 - (2) After 5 min later power on again and wait until booting is completed.
 - (3) Repeat (2) for around 4:50
 - (4) Power off then wait for 5 min before final power on operation.
3. Number of test: 50 times
4. Test Software: Windows CE from CFD
5. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AOP-8060WT Fanless Operator Panel PC)

Test Result:

Passed.